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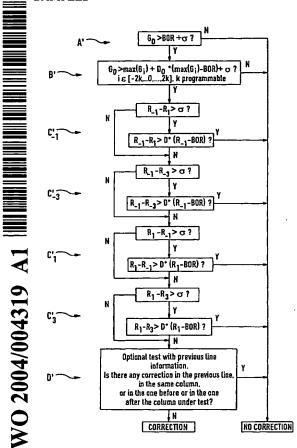
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(54) Title: DEVICE AND METHOD OF DETECTION OF ERRONEOUS IMAGE SAMPLE DATA OF DEFECTIVE IMAGE SAMPLES



(57) Abstract: A real-time pixel correction algorithm is proposed for on-the-fly repair of pixel information from dead or disturbed pixels from a pixel array. The algorithm can be used for both CCD and CMOS imagers.